

## OptiMOS™2 Power-Transistor

### Features

- Fast switching MOSFET for SMPS
- Optimized technology for notebook DC/DC converters
- Qualified according to JEDEC<sup>1)</sup> for target applications
- N-channel
- Logic level
- Excellent gate charge  $\times R_{DS(on)}$  product (FOM)
- Very low on-resistance  $R_{DS(on)}$
- Superior thermal resistance
- Avalanche rated
- Pb-free plating; RoHS compliant
- Halogen-free according to IEC61249-2-21

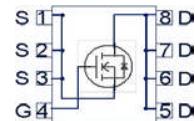
### Product Summary

$V_{DS}$	30	V
$R_{DS(on),max}$	6.4	$m\Omega$
$I_D$	16	A

PG-DSO-8



Type	Package	Marking
BSO064N03S	PG-DSO-8	064N3S



**Maximum ratings**, at  $T_j=25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Conditions	Value		Unit
			10 secs	steady state	
Continuous drain current	$I_D$	$T_A=25^\circ\text{C}^2)$	16	12	A
		$T_A=70^\circ\text{C}^2)$	12	9.9	
Pulsed drain current	$I_{D,pulse}$	$T_A=25^\circ\text{C}^3)$	64		
Avalanche energy, single pulse	$E_{AS}$	$I_D=16\text{ A}, R_{GS}=25\ \Omega$	170		mJ
Reverse diode dv/dt	dv/dt	$I_D=16\text{ A}, V_{DS}=20\text{ V}, di/dt=200\text{ A}/\mu\text{s}, T_{j,max}=150^\circ\text{C}$	6		kV/ $\mu$ s
Gate source voltage	$V_{GS}$		$\pm 20$		V
Power dissipation	$P_{tot}$	$T_A=25^\circ\text{C}^2)$	2.5	1.56	W
Operating and storage temperature	$T_j, T_{stg}$		-55 ... 150		°C
IEC climatic category; DIN IEC 68-1			55/150/56		

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
<b>Thermal characteristics</b>						
Thermal resistance, junction - soldering point	$R_{thJS}$		-	-	35	K/W
Thermal resistance, junction - ambient	$R_{thJA}$	minimal footprint, $t_p \leq 10$ s	-	-	110	
		minimal footprint, steady state	-	-	150	
		6 cm <sup>2</sup> cooling area <sup>2)</sup> , $t_p \leq 10$ s	-	-	50	
		6 cm <sup>2</sup> cooling area <sup>2)</sup> , steady state	-	-	80	

**Electrical characteristics**, at  $T_j=25$  °C, unless otherwise specified

#### Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0$ V, $I_D=1$ mA	30	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$ , $I_D=50$ µA	1.2	1.6	2	
Zero gate voltage drain current	$I_{DSS}$	$V_{DS}=30$ V, $V_{GS}=0$ V, $T_j=25$ °C	-	0.1	1	µA
		$V_{DS}=30$ V, $V_{GS}=0$ V, $T_j=125$ °C	-	10	100	
Gate-source leakage current	$I_{GSS}$	$V_{GS}=20$ V, $V_{DS}=0$ V	-	10	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=4.5$ V, $I_D=14$ A	-	7.0	8.8	mΩ
		$V_{GS}=10$ V, $I_D=16$ A	-	5.3	6.4	
Gate resistance	$R_G$		-	0.9	-	Ω
Transconductance	$g_{fs}$	$ V_{DS} >2 I_D R_{DS(on)max},$ $I_D=16$ A	26	51	-	s

<sup>1)</sup>J-STD20 and JESD22

<sup>2)</sup> Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

<sup>3)</sup> See figure 3

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

**Dynamic characteristics**

Input capacitance	$C_{iss}$	$V_{GS}=0 \text{ V}, V_{DS}=15 \text{ V}, f=1 \text{ MHz}$	-	2720	3620	pF
Output capacitance	$C_{oss}$		-	970	1290	
Reverse transfer capacitance	$C_{rss}$		-	120	180	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=15 \text{ V}, V_{GS}=10 \text{ V}, I_D=8 \text{ A}, R_G=2.7 \Omega$	-	6.7	10	ns
Rise time	$t_r$		-	5.8	8.7	
Turn-off delay time	$t_{d(off)}$		-	29	43	
Fall time	$t_f$		-	4.2	6.3	

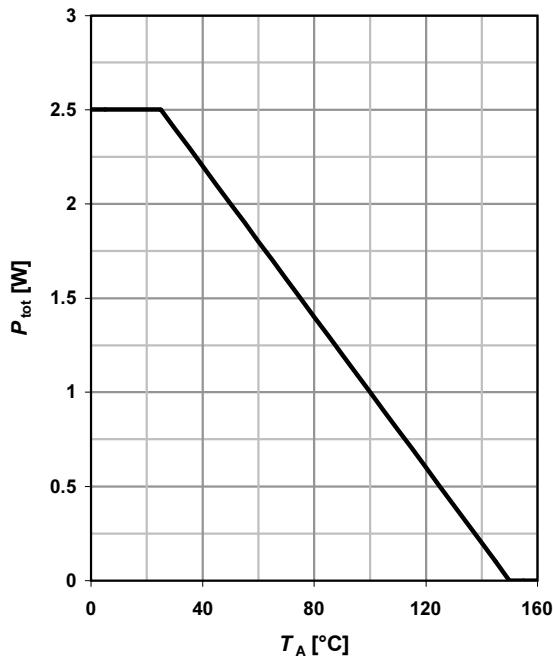
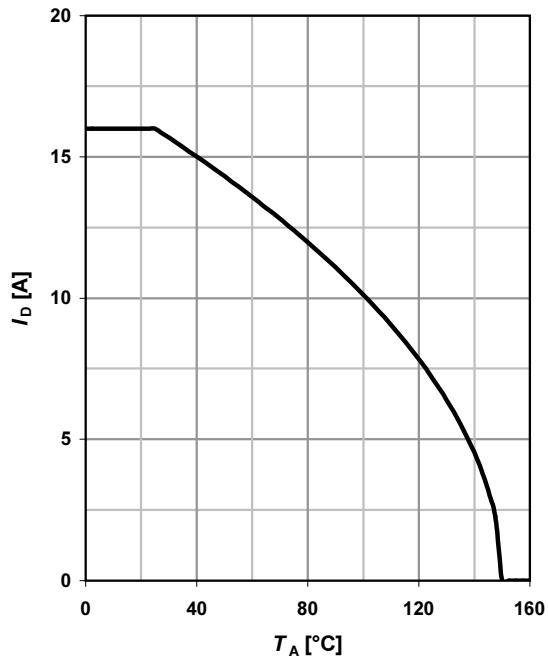
**Gate Charge Characteristics<sup>4)</sup>**

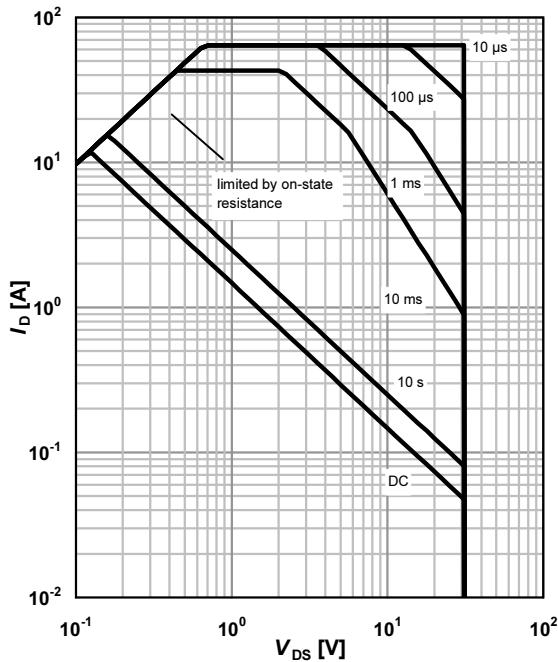
Gate to source charge	$Q_{gs}$	$V_{DD}=15 \text{ V}, I_D=8 \text{ A}, V_{GS}=0 \text{ to } 5 \text{ V}$	-	7.4	10	nC
Gate charge at threshold	$Q_{g(th)}$		-	4.3	5.8	
Gate to drain charge	$Q_{gd}$		-	5.0	7.5	
Switching charge	$Q_{sw}$		-	8.1	12	
Gate charge total	$Q_g$		-	21	28	
Gate plateau voltage	$V_{plateau}$		-	2.7	-	
Gate charge total, sync. FET	$Q_{g(sync)}$	$V_{DS}=0.1 \text{ V}, V_{GS}=0 \text{ to } 5 \text{ V}$	-	18	25	nC
Output charge	$Q_{oss}$	$V_{DD}=15 \text{ V}, V_{GS}=0 \text{ V}$	-	23	31	

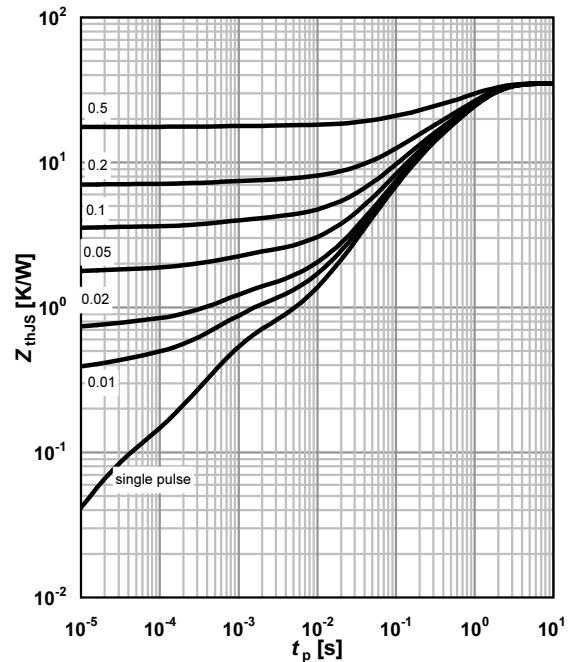
**Reverse Diode**

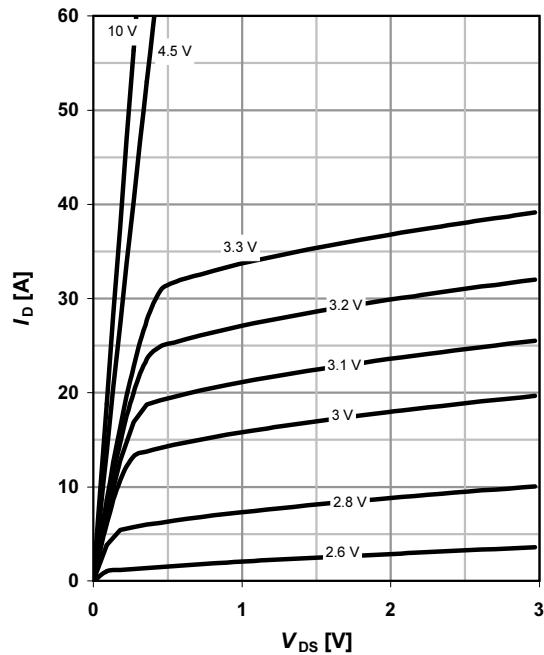
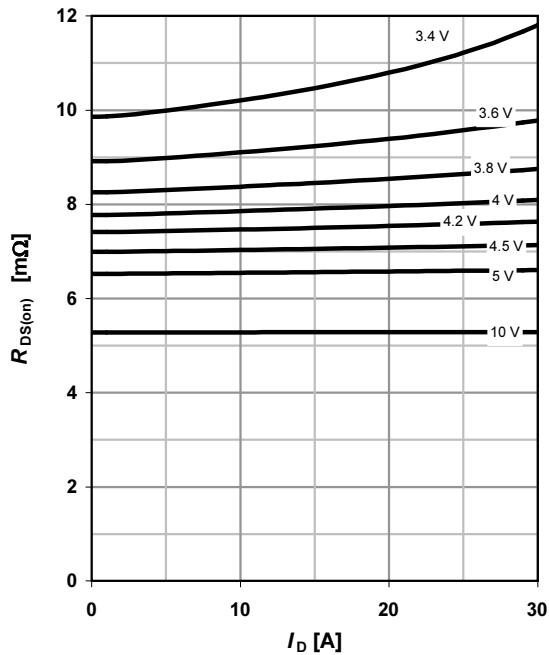
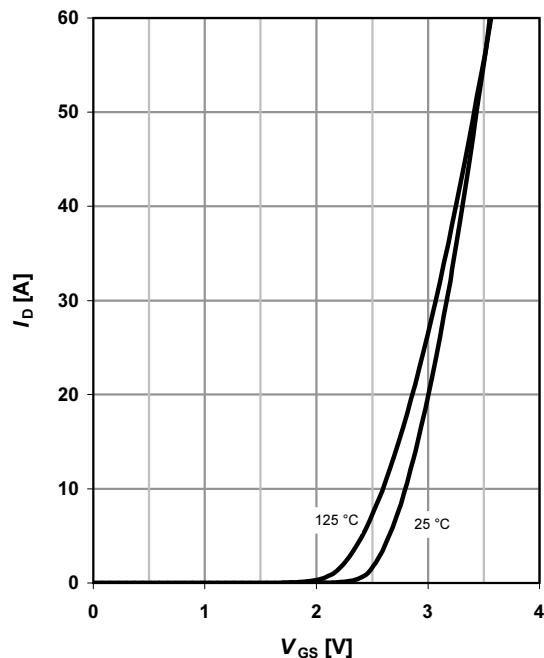
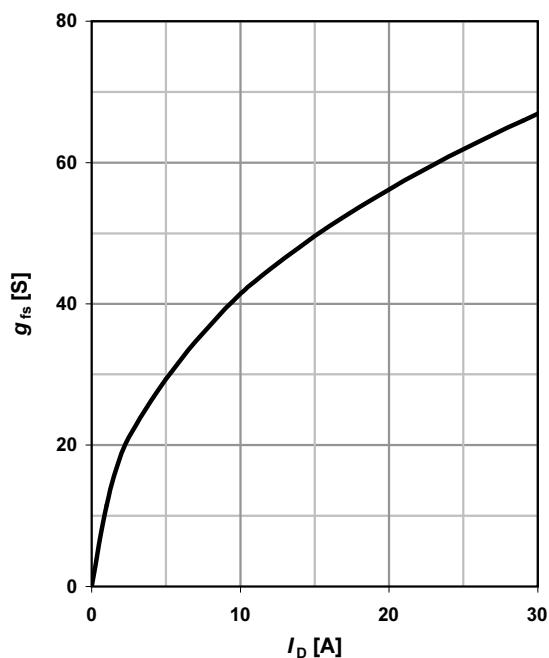
Diode continuous forward current	$I_s$	$T_A=25 \text{ }^\circ\text{C}$	-	-	2.5	A
Diode pulse current	$I_{s,pulse}$		-	-	64	
Diode forward voltage	$V_{SD}$	$V_{GS}=0 \text{ V}, I_F=2.5 \text{ A}, T_j=25 \text{ }^\circ\text{C}$	-	0.73	1	
Reverse recovery charge	$Q_{rr}$	$V_R=15 \text{ V}, I_F=I_s, di_F/dt=400 \text{ A}/\mu\text{s}$	-	-	10	

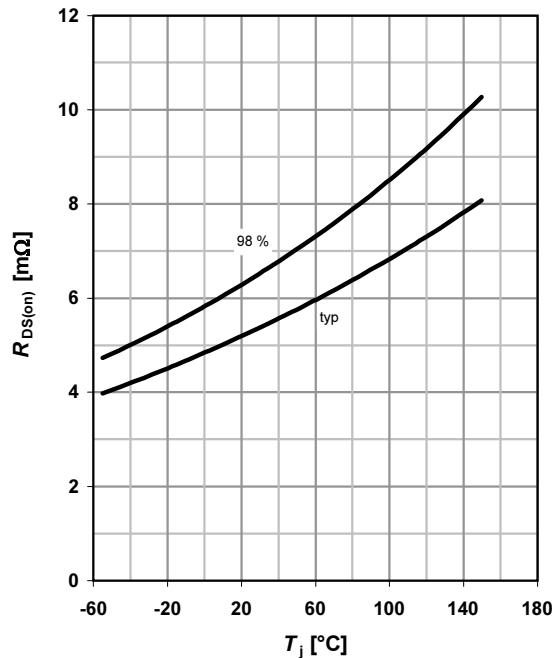
<sup>4)</sup> See figure 16 for gate charge parameter definition

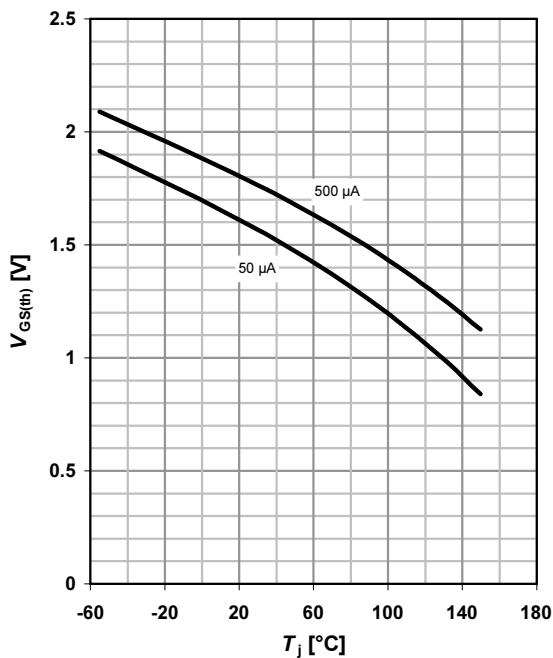
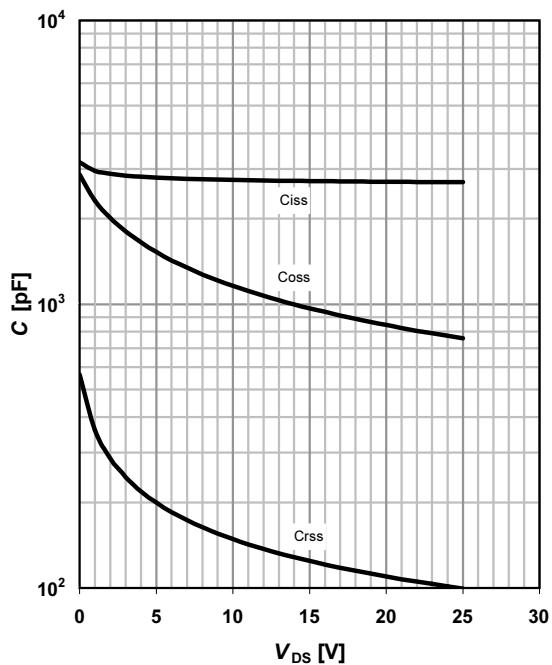
**1 Power dissipation**
 $P_{\text{tot}} = f(T_A); t_p \leq 10 \text{ s}$ 

**2 Drain current**
 $I_D = f(T_A); V_{GS} \geq 10 \text{ V}; t_p \leq 10 \text{ s}$ 

**3 Safe operating area**
 $I_D = f(V_{DS}); T_A = 25 \text{ }^{\circ}\text{C}^1, D = 0$ 

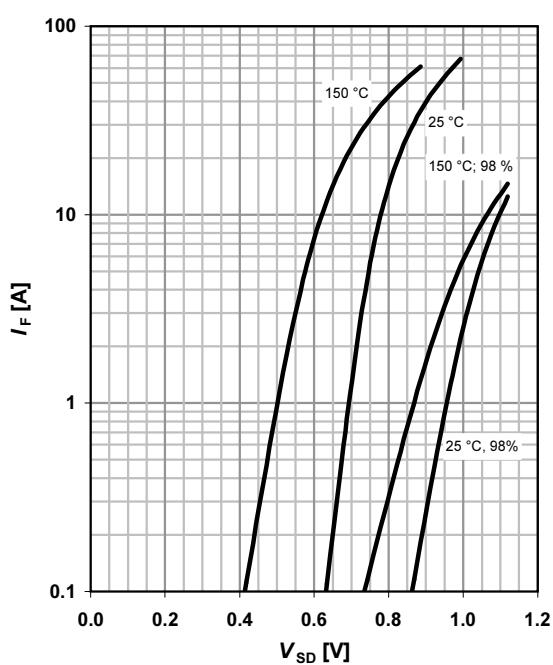
parameter:  $t_p$ 

**4 Max. transient thermal impedance**
 $Z_{\text{thJS}} = f(t_p)$ 

parameter:  $D = t_p/T$ 


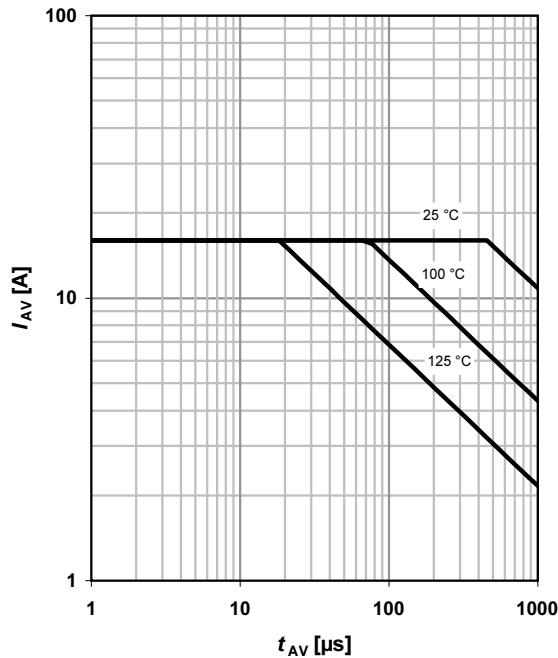
**5 Typ. output characteristics**
 $I_D = f(V_{DS})$ ;  $T_j = 25 \text{ }^\circ\text{C}$ 
parameter:  $V_{GS}$ 
**6 Typ. drain-source on resistance**
 $R_{DS(on)} = f(I_D)$ ;  $T_j = 25 \text{ }^\circ\text{C}$ 
parameter:  $V_{GS}$ 
**7 Typ. transfer characteristics**
 $I_D = f(V_{GS})$ ;  $|V_{DS}| > 2|I_D|R_{DS(on)max}$ 
parameter:  $T_j$ 
**8 Typ. forward transconductance**
 $g_{fs} = f(I_D)$ ;  $T_j = 25 \text{ }^\circ\text{C}$ 


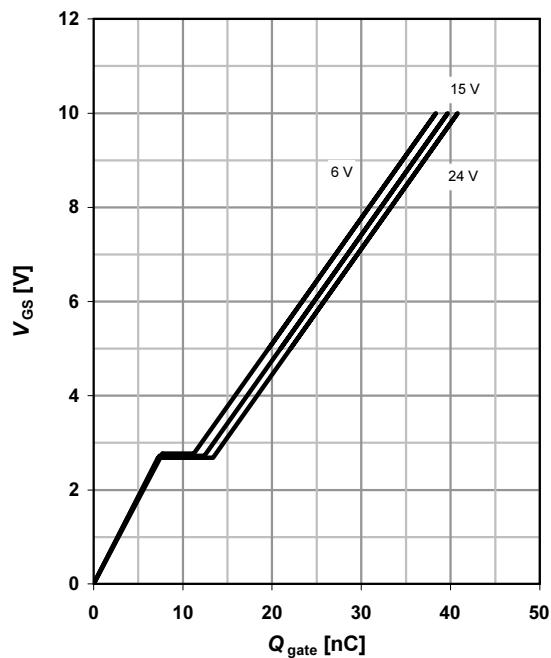
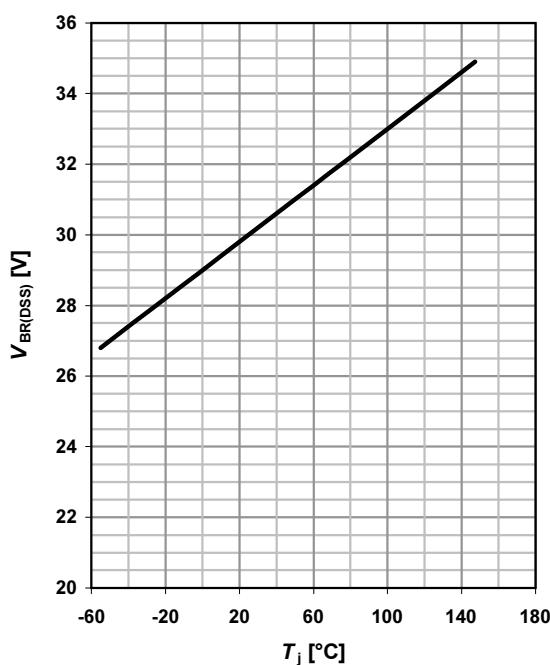
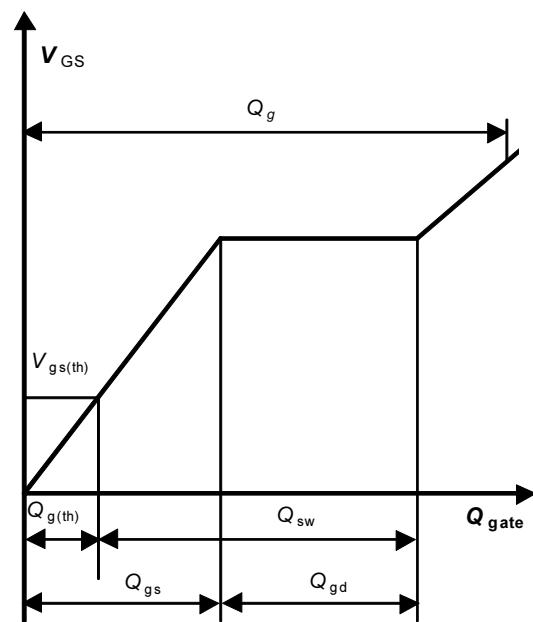
**9 Drain-source on-state resistance**
 $R_{DS(on)} = f(T_j); I_D = 16 \text{ A}; V_{GS} = 10 \text{ V}$ 

**10 Typ. gate threshold voltage**
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

 parameter:  $I_D$ 

**11 Typ. capacitances**
 $C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$ 

**12 Forward characteristics of reverse diode**
 $I_F = f(V_{SD})$ 

 parameter:  $T_j$ 


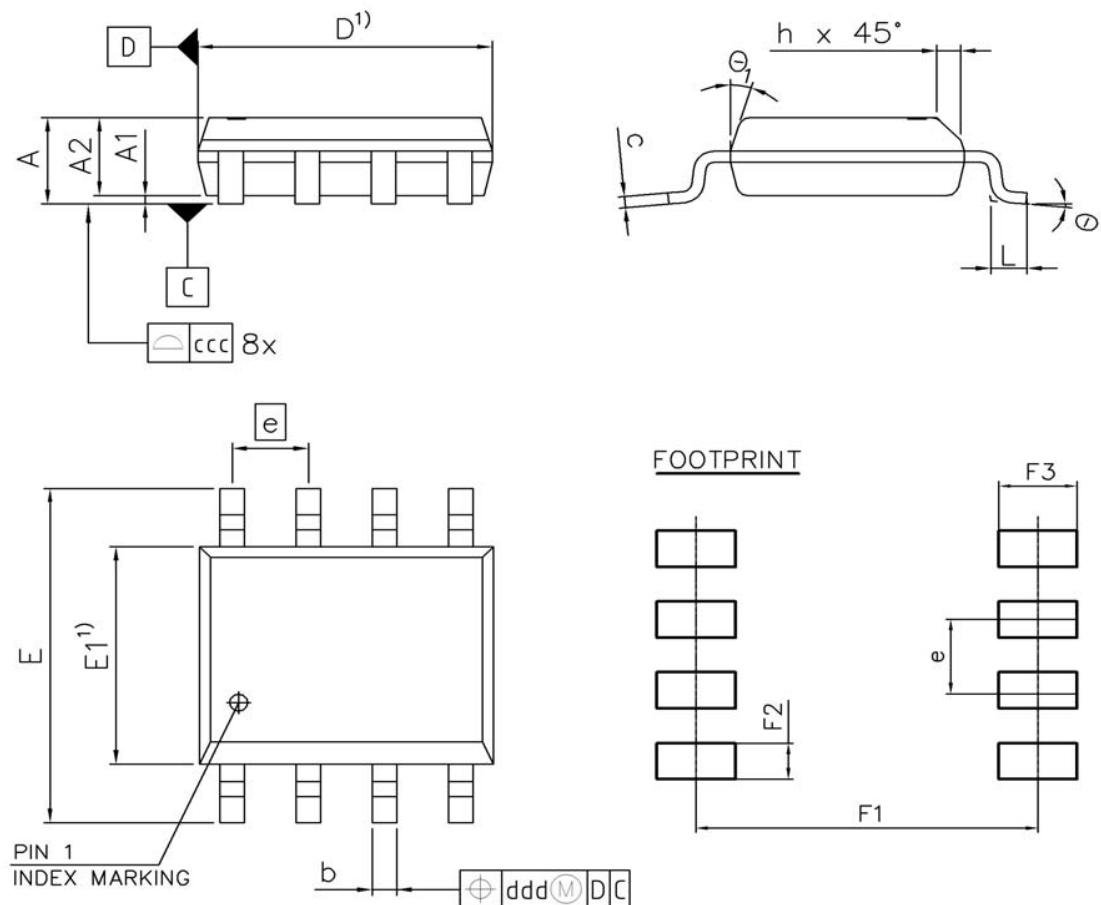
**13 Avalanche characteristics**
 $I_{AV} = f(t_{AV})$ ;  $R_{GS} = 25 \Omega$ 

parameter:  $T_j(\text{start})$ 

**14 Typ. gate charge**
 $V_{GS} = f(Q_{\text{gate}})$ ;  $I_D = 8 \text{ A pulsed}$ 

parameter:  $V_{DD}$ 

**15 Drain-source breakdown voltage**
 $V_{BR(DSS)} = f(T_j)$ ;  $I_D = 1 \text{ mA}$ 

**16 Gate charge waveforms**


## Package Outline

## PG-DSO-8



1) DOES NOT INCLUDE MOLD FLASH OR PROTRUSIONS.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	-	1.75	-	0.069
A1	0.10	-	0.004	-
A2	1.25	1.65	0.049	0.065
b	0.35	0.51	0.014	0.020
c	0.17	0.25	0.007	0.010
D	4.80	5.00	0.189	0.197
E	5.80	6.20	0.228	0.244
E1	3.80	4.00	0.150	0.157
e	1.27		0.050	
N	8		8	
L	0.39	0.89	0.015	0.035
h	0.23	0.50	0.009	0.020
θ	0°	8°	0°	8°
θ <sub>1</sub>	-	19°	-	19°
ccc	0.10		0.004	
ddd	0.25		0.010	
F1	5.59	5.79	0.220	0.228
F2	0.55	0.75	0.022	0.030
F3	1.21	1.41	0.048	0.056

DOCUMENT NO.	Z8B00003333
SCALE	0 1.0 0 1.0 2mm
EUROPEAN PROJECTION	
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